

August 2007

FDFMJ2P023Z

Integrated P-Channel PowerTrench® MOSFET and Schottky Diode –20V, –2.9A, 112m Ω

Features

MOSFET

- Max $r_{DS(on)} = 112m\Omega$ at $V_{GS} = -4.5V$, $I_D = -2.9A$
- Max $r_{DS(on)} = 160 \text{m}\Omega$ at $V_{GS} = -2.5 \text{V}$, $I_D = -2.4 \text{A}$
- Max $r_{DS(on)} = 210m\Omega$ at $V_{GS} = -1.8V$, $I_D = -2.1A$
- Max $r_{DS(on)} = 300 m\Omega$ at $V_{GS} = -1.5 V$, $I_D = -1.0 A$
- Low gate charge, high power and current handline capability
- HBM ESD protection level > 1.5KV typical (Note 3)

Schottky

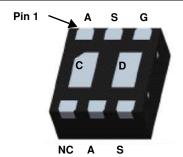
- V_F < 400mV @ 100mA
- RoHS Compliant



General Description

This device is designed specifically as a single package solution for the battery charge switch in cellular handset and other ultra-portable applications. It features a MOSFET with low on-state resistance and an independently connected low forward voltage schottky diode for minimum conduction losses.

The SC-75 MicroFET package offers exceptional thermal performance for it's physical size and is well suited to linear mode applications.



SC-75 MicroFET

TO BOTTOM 6 NC S 2 5 A G 3 TO BOTTOM

MOSFET Maximum Ratings T_A = 25°C unless otherwise noted

Symbol	Parameter	Parameter		
V_{DS}	Drain to Source Voltage		-20	V
V_{GS}	Gate to Source Voltage		±8	V
	Drain Current -Continuous	(Note 1a)	-2.9	۸
I _D	-Pulsed		-12	A
В	Power Dissipation	(Note 1a)	1.4	W
P_{D}	Power Dissipation	(Note 1b)	0.7	VV
T _J , T _{STG}	Operating and Storage Junction Temperature Range	-55 to +150	°C	
V_{RRM}	Schottky Repetitive Peak Reverse Voltage 30		30	V
Io	Schottky Average Forward Current		1	Α

Thermal Characteristics

$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	(Note 1a)	89	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	(Note 1b)	182	C/VV

Package Marking and Ordering Information

Device Marking	Device	Package	Package Reel Size		Quantity
.P23	FDFMJ2P023Z	SC-75 MicroFET	7"	8 mm	3000 units

Electrical Characteristics T_J = 25°C unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Chara	acteristics					
BV_{DSS}	Drain to Source Breakdown Voltage	$I_D = -250 \mu A, V_{GS} = 0 V$	-20			V
$\frac{\Delta BV_{DSS}}{\Delta T_{J}}$	Breakdown Voltage Temperature Coefficient	$I_D = -250\mu\text{A}$, referenced to 25°C		-13		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = -16V, V_{GS} = 0V$			-1	μА
I _{GSS}	Gate to Source Leakage Current	$V_{GS} = \pm 8V, V_{DS} = 0V$			±10	μА

On Characteristics

V _{GS(th)}	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_{D} = -250 \mu A$	-0.4	-0.7	-1.0	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	$I_D = -250\mu\text{A}$, referenced to 25°C		2.3		mV/°C
,	$V_{GS} = -4.5V$, $I_D = -2.9A$		93	112		
		$V_{GS} = -2.5V$, $I_D = -2.4A$		128	160	
r _{DS(on)}	Static Drain to Source On Resistance	$V_{GS} = -1.8V$, $I_D = -2.1A$		173	210	mΩ
		$V_{GS} = -1.5V$, $I_D = -1.0A$		217	300	
		$V_{GS} = -4.5V$, $I_D = -2.9A$, $T_J = 125$ °C		130	160	
9 _{FS}	Forward Transconductance	$V_{DS} = -5V$, $I_D = -2.9A$		7		S

Dynamic Characteristics

C _{iss}	Input Capacitance	V 10V V 0V	300	400	pF
C _{oss}	Output Capacitance	$V_{DS} = -10V, V_{GS} = 0V,$ $f = 1MHz$	55	75	pF
C _{rss}	Reverse Transfer Capacitance	1 - 110112	45	70	pF

Switching Characteristics

$t_{d(on)}$	Turn-On Delay Time		5	10	ns
t _r	Rise Time	$V_{DD} = -10V, I_{D} = -2.9A$ $V_{GS} = -4.5V, R_{GEN} = 6\Omega$	4	10	ns
t _{d(off)}	Turn-Off Delay Time	$V_{GS} = -4.5V$, $n_{GEN} = 602$	23	37	ns
t _f	Fall Time		12	22	ns
Q_g	Total Gate Charge	V 5V 1 00A	4.6	6.5	nC
Q_{gs}	Gate to Source Charge	$V_{DD} = -5V, I_{D} = -2.9A$ $V_{GS} = -4.5V$	0.6		nC
Q_{gd}	Gate to Drain "Miller" Charge	*GS = 4.0*	1.0		nC

Drain-Source Diode Characteristics

I _S	Maximum Continuous Drain-Source Diode Forward Current			-1.1	Α
V_{SD}	Source to Drain Diode Forward Voltage	$V_{GS} = 0V, I_S = -1.1A$	-0.9	-1.2	V
t _{rr}	Reverse Recovery Time	I _F = -2.9A, di/dt = 100A/μs	28	45	ns
Q _{rr}	Reverse Recovery Charge	$71F = -2.9A$, $01/01 = 100A/\mu$ S	15	27	nC

Electrical Characteristics $T_J = 25$ °C unless otherwise noted

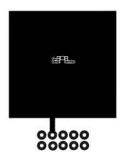
Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Cobottley	Diede Characteristics					

Schottky Diode Characteristics

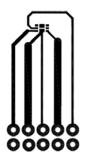
V_{R}	Reverse Voltage	I _R = 100mA	$T_J = 25^{\circ}C$	30			V
			$T_J = 25^{\circ}C$		0.39	2	μΑ
I_R	Reverse Leakage	$V_R = 10V$	$T_J = 85^{\circ}C$		0.04	0.2	mA
			$T_J = 125$ °C		0.4	2	mA
			$T_J = 25^{\circ}C$		0.86	4	μΑ
I_R	Reverse Leakage	$V_R = 20V$	$T_J = 85^{\circ}C$		0.06	0.3	mA
			$T_J = 125$ °C		0.62	3	mA
			$T_J = 25^{\circ}C$		380	400	mV
V_{F}	Forward Voltage	$I_F = 100 \text{mA}$	$T_J = 85^{\circ}C$		300	350	mV
			$T_J = 125$ °C		250	300	mV
			$T_J = 25^{\circ}C$		570	615	mV
V_{F}	Forward Voltage	I _F = 1A	$T_J = 85^{\circ}C$		540	590	mV
			$T_J = 125$ °C		530	580	mV

Notes

1. R_{e,JA} is determined with the device mounted on a 1in² pad 2 oz copper pad on a 1.5 x 1.5 in. board of FR-4 material. R_{e,JC} is guaranteed by design while R_{eCA} is determined by the user's board design.



a. 89°C/W when mounted on a 1 in² pad of 2 oz copper



b.182°C/W when mounted on a minimum pad of 2 oz copper

- 2. Pulse Test: Pulse Width < 300 $\mu s,$ Duty cycle < 2.0%.
- 3. The diode connected between the gate and source serves only as protection against ESD. No gate overvoltage rating is implied.

Typical Characteristics T_J = 25°C unless otherwise noted

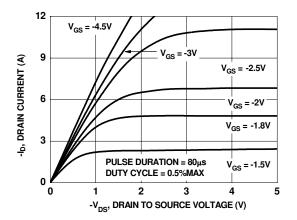


Figure 1. On-Region Characteristics

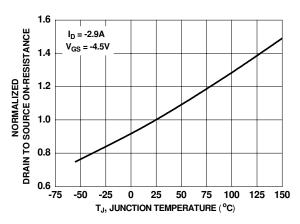


Figure 3. Normalized On-Resistance vs Junction Temperature

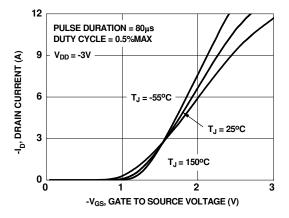


Figure 5. Transfer Characteristics

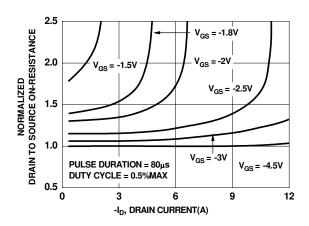


Figure 2. Normalized On-Resistance vs Drain Current and Gate Voltage

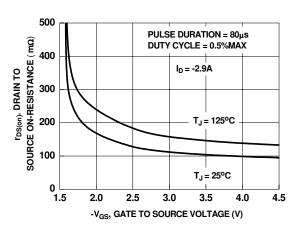


Figure 4. On-Resistance vs Gate to Source Voltage

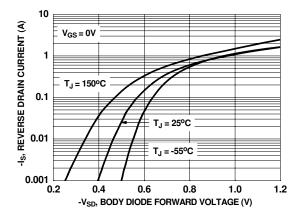


Figure 6. Source to Drain Diode Forward Voltage vs Source Current

Typical Characteristics T_J = 25°C unless otherwise noted

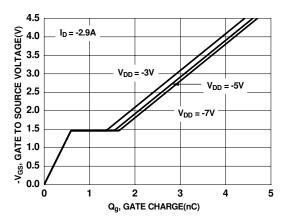


Figure 7. Gate Charge Characteristics

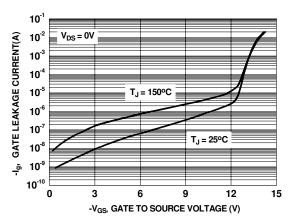


Figure 9. Gate Leakage Current vs Gate to Source Voltage

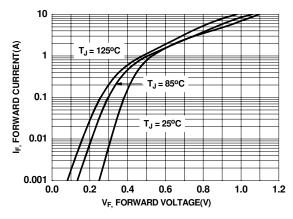


Figure 11. Schottky Diode Forward Voltage

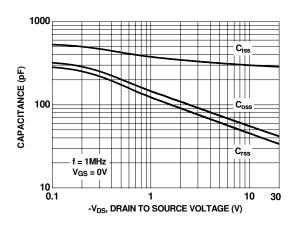


Figure 8. Capacitance vs Drain to Source Voltage

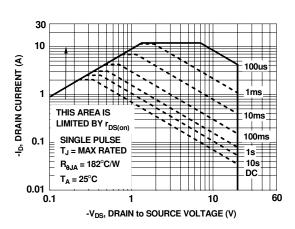


Figure 10. Forward Bias Safe Operating Area

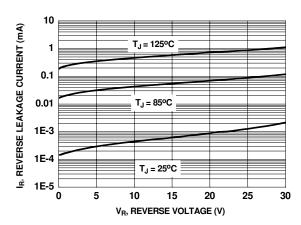


Figure 12. Schottky Diode Reverse Current

Typical Characteristics $T_J = 25^{\circ}C$ unless otherwise noted

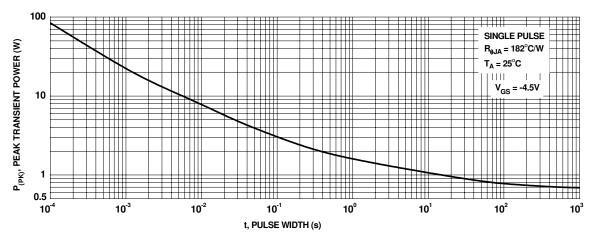


Figure 13. Single Pulse Maximum Power Dissipation

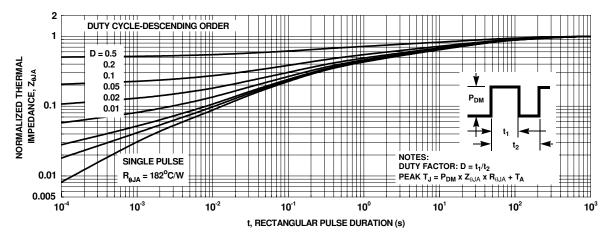
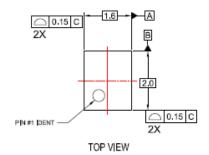
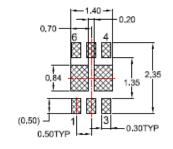


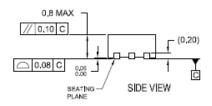
Figure 14. Transient Thermal Response Curve

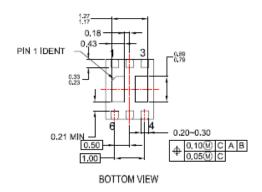
Dimensional Outline and Pad Layout





RECOMMENDED LAND PATTERN







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